

**FCC ID: 2AGA9WD03**

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances  $\leq$  50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot [\sqrt{f(\text{GHz})}] \leq 3.0 \text{ for 1-g SAR and } \leq 7.5 \text{ for 10-g extremity SAR, where:}$

- $f(\text{GHz})$  is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is  $<$  5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BR+EDR:

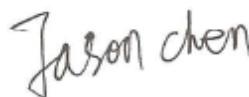
Antenna Type: PCB Antenna

Antenna Gain: 0 dBi

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	1g SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	3.89	2.449	4±1	5.0	3.162	<5	0.98020	3.00	YES
	2.441	4.88	3.076	4±1	5.0	3.162	<5	0.98813	3.00	YES
	2.480	4.95	3.126	4±1	5.0	3.162	<5	0.99599	3.00	YES
$\pi/4$ -DQPSK	2.402	3.92	2.466	4±1	5.0	3.162	<5	0.98020	3.00	YES
	2.441	4.90	3.090	4±1	5.0	3.162	<5	0.98813	3.00	YES
	2.480	4.96	3.133	4±1	5.0	3.162	<5	0.99599	3.00	YES
8DPSK	2.402	3.93	2.472	3±1	4.0	2.512	<5	0.77860	3.00	YES
	2.441	4.95	3.126	3±1	4.0	2.512	<5	0.78490	3.00	YES
	2.480	4.99	3.155	3±1	4.0	2.512	<5	0.79114	3.00	YES

**Conclusion:**

For the max result :  $0.99599 \leq 3.0$  for 1-g SAR, No SAR is required.



Signature:

Date: 2018-1-18

**NAME AND TITLE** (Please print or type): Jason Chen /Manager

**COMPANY** (Please print or type): Shenzhen NTEK Testing Technology Co., Ltd./ 1/F, Building E, Fenda Science Park, Sanwei Community, Xixiang Street Bao'an District, Shenzhen 518126 P.R. China